

## Automotive-grade N-channel 600 V, 0.17 $\Omega$ typ., 17 A FDmesh™ II Power MOSFET in a TO-220FP package

Datasheet - production data

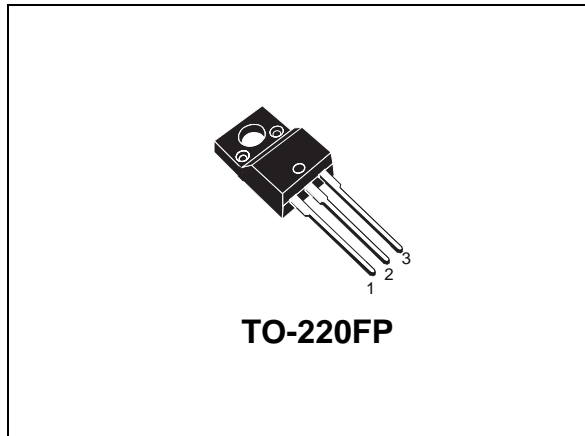
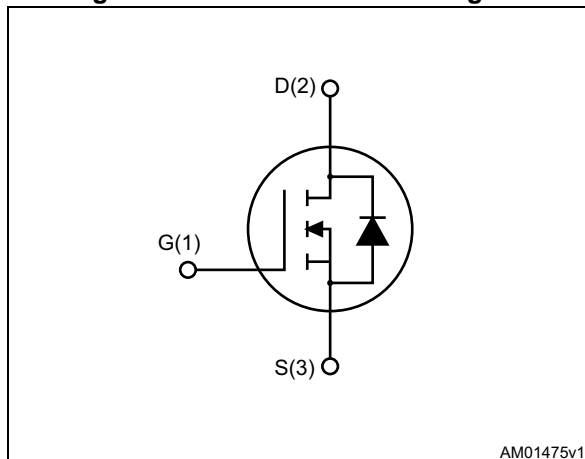


Figure 1. Internal schematic diagram



### Features

Order code	$V_{DS}$ @ $T_{Jmax}$	$R_{DS(on)}$ max	$I_D$
STF22NM60ND	650 V	0.22 $\Omega$	17 A

- Designed for automotive applications and AEC-Q101 qualified
- Fast-recovery body diode
- Low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- High dv/dt ruggedness

### Applications

- Switching applications

### Description

This FDmesh™ II Power MOSFET with fast-recovery body diode is produced using MDmesh™ II technology. Utilizing a new strip-layout vertical structure, this device features low on-resistance and superior switching performance. It is ideal for bridge topologies and ZVS phase-shift converters.

Table 1. Device summary

Order code	Marking	Package	Packing
STF22NM60ND	22NM60ND	TO-220FP	Tube

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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	600	V
$V_{GS}$	Gate- source voltage	$\pm 25$	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$	17	A
	Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$	10	
$I_{DM}^{(1)(2)}$	Drain current (pulsed)	68	A
$P_{TOT}$	Total dissipation at $T_C = 25\text{ }^\circ\text{C}$	30	W
$dv/dt^{(3)}$	Peak diode recovery voltage slope	40	V/ns
$V_{ISO}$	Insulation withstand voltage (RMS) from all three leads to external heat sink ( $t=1\text{ s}; T_C= 25\text{ }^\circ\text{C}$ )	2500	V
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_J$	Operating junction temperature		

- Limited by maximum junction temperature.
- Pulse width limited by safe operating area.
- $I_{SD} \leq 17\text{ A}$ ,  $di/dt \leq 600\text{ A}/\mu\text{s}$ ,  $V_{DD} = 80\% V_{(BR)DSS}$ ,  $V_{DS(peak)} \leq V_{(BR)DSS}$

**Table 3. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	4.17	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5	

**Table 4. Avalanche characteristics**

Symbol	Parameter	Max value	Unit
$I_{AS}$	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_J$ max)	8.5	A
$E_{AS}$	Single pulse avalanche energy (starting $T_J = 25\text{ }^\circ\text{C}$ , $I_D = I_{AS}$ , $V_{DD} = 50\text{ V}$ )	610	mJ

## 2 Electrical characteristics

(T<sub>CASE</sub> = 25°C unless otherwise specified)

**Table 5. On/off states**

Symbol	Parameter	Test conditions	Value			Unit
			Min.	Typ.	Max.	
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0	600			V
dv/dt <sup>(1)</sup>	Drain source voltage slope	V <sub>DD</sub> = 480 V, I <sub>D</sub> = 17 A, V <sub>GS</sub> = 10 V	36			V/ns
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = 600 V			10	µA
		V <sub>DS</sub> = 600 V, T <sub>C</sub> = 125 °C			100	µA
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 µA	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 8.5 A		0.170	0.220	Ω

1. Characteristic value at turn off on inductive load

**Table 6. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit	
C <sub>iss</sub>	Input capacitance	V <sub>DS</sub> = 50 V, f = 1 MHz, V <sub>GS</sub> = 0	-	1800	-	pF	
C <sub>oss</sub>	Output capacitance			90		pF	
C <sub>rss</sub>	Reverse transfer capacitance				8		pF
C <sub>oss eq.</sub> <sup>(1)</sup>	Equivalent output capacitance	V <sub>GS</sub> = 0, V <sub>DS</sub> = 0 to 480 V	-	300	-	pF	
t <sub>d(on)</sub>	Turn-on delay time	V <sub>DD</sub> = 300 V, I <sub>D</sub> = 8.5 A R <sub>G</sub> = 4.7 Ω, V <sub>GS</sub> = 10 V (see Figure 19), (see Figure 14)	-	18	-	ns	
t <sub>r</sub>	Rise time			16		ns	
t <sub>d(off)</sub>	Turn-off delay time				70		ns
t <sub>f</sub>	Fall time				48		ns
Q <sub>g</sub>	Total gate charge	V <sub>DD</sub> = 480 V, I <sub>D</sub> = 17 A, V <sub>GS</sub> = 10 V, (see Figure 15)	-	60		nC	
Q <sub>gs</sub>	Gate-source charge			13		nC	
Q <sub>gd</sub>	Gate-drain charge			30	-	nC	
R <sub>G</sub>	Gate input resistance	f = 1 MHz Gate DC Bias = 0 Test signal level = 20 mV Open drain	-	3	-	Ω	

1. C<sub>oss eq.</sub> is defined as a constant equivalent capacitance giving the same charging time as C<sub>oss</sub> when V<sub>DS</sub> increases from 0 to 80% V<sub>DSS</sub>

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current				17	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				68	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 17\text{ A}, V_{GS} = 0$			1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 17\text{ A}, V_{DD} = 60\text{ V}$ $di/dt = 100\text{ A}/\mu\text{s}$ (see Figure 16)		150		ns
$Q_{rr}$	Reverse recovery charge			0.90		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current			13		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 17\text{ A}, V_{DD} = 60\text{ V}$ $di/dt = 100\text{ A}/\mu\text{s}$ , $T_J = 150\text{ }^\circ\text{C}$ (see Figure 16)		240		ns
$Q_{rr}$	Reverse recovery charge			2		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current			16		A

1. Pulse width limited by safe operating area
2. Pulsed: Pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

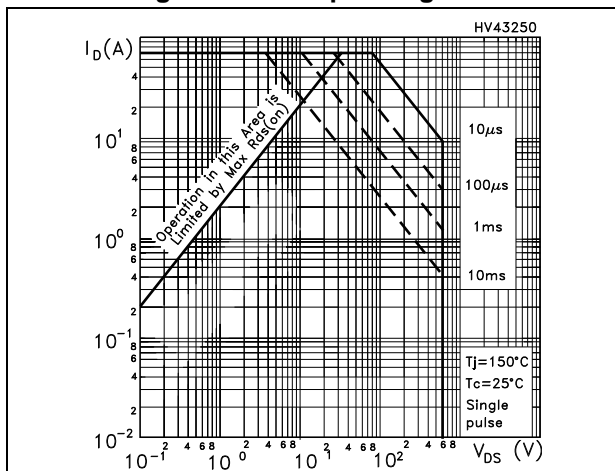


Figure 3. Thermal impedance

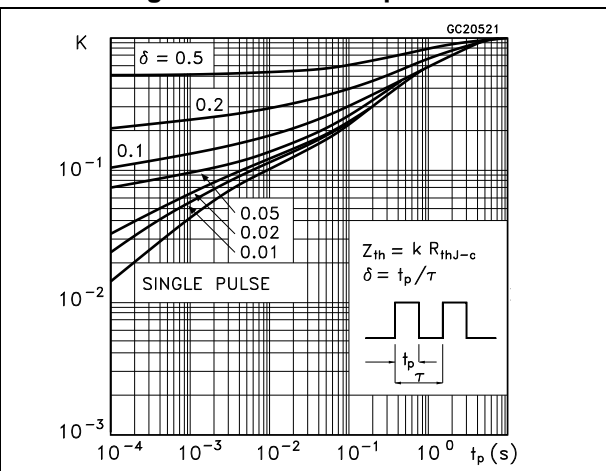


Figure 4. Output characteristics

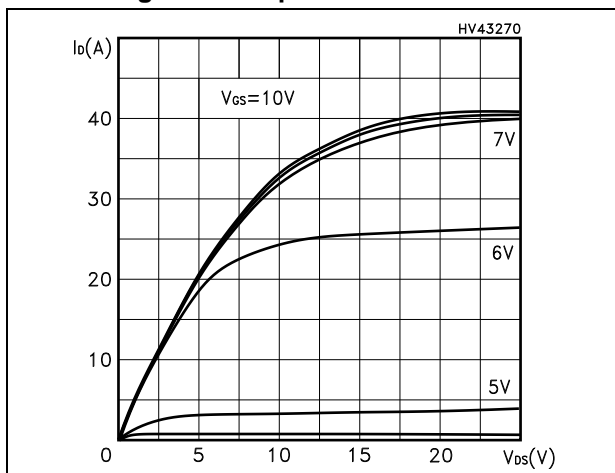


Figure 5. Transfer characteristics

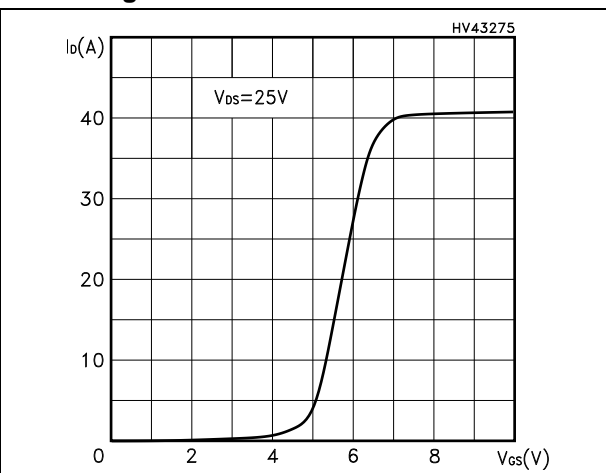


Figure 6. Transconductance

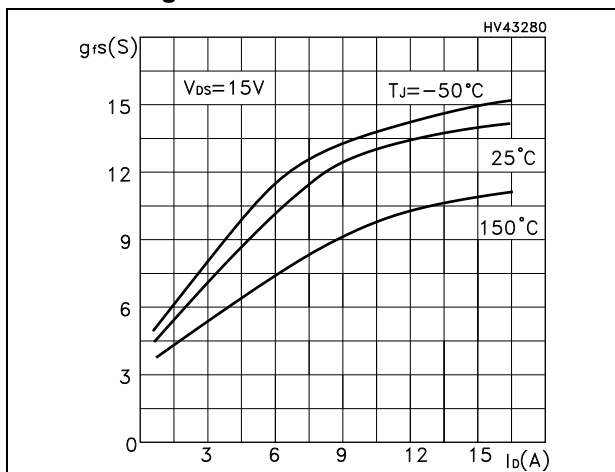


Figure 7. Static drain-source on-resistance

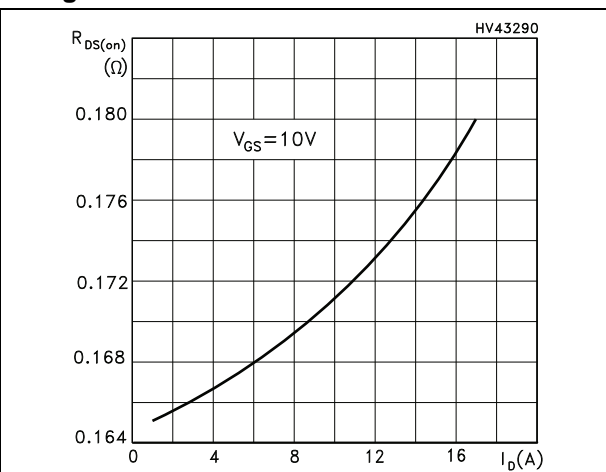


Figure 8. Gate charge vs gate-source voltage

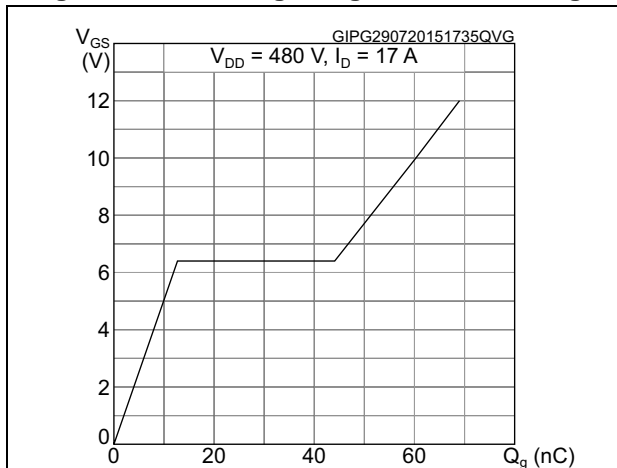


Figure 9. Capacitance variations

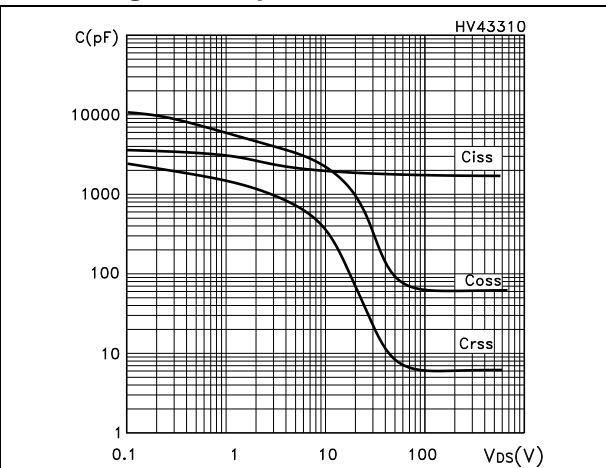


Figure 10. Normalized gate threshold voltage vs temperature

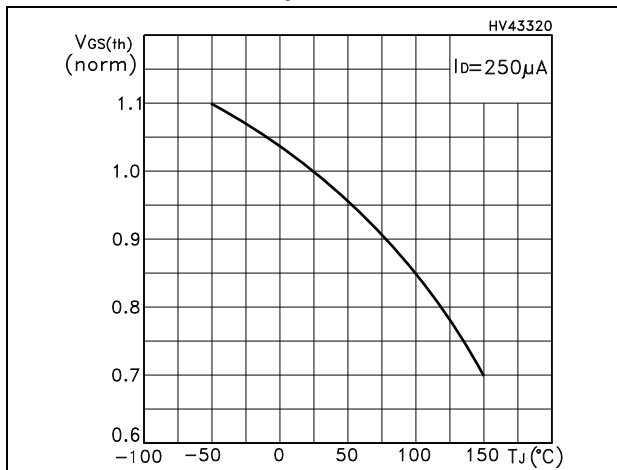


Figure 11. Normalized on-resistance vs temperature

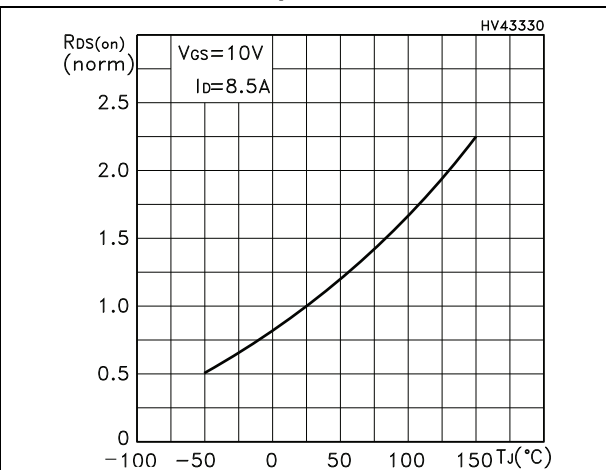


Figure 12. Source-drain diode forward characteristics

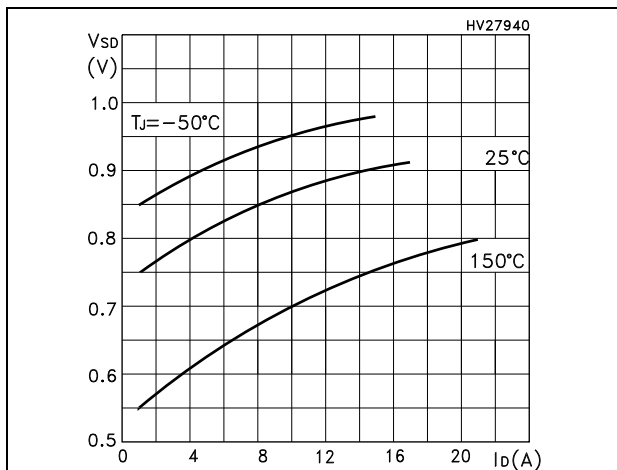
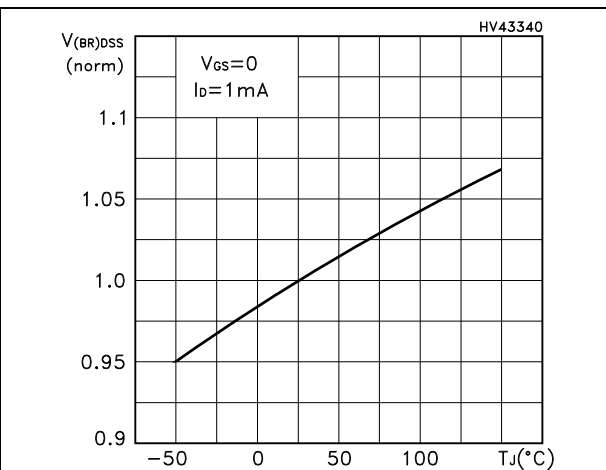


Figure 13. Normalized  $V_{(BR)DSS}$  vs temperature



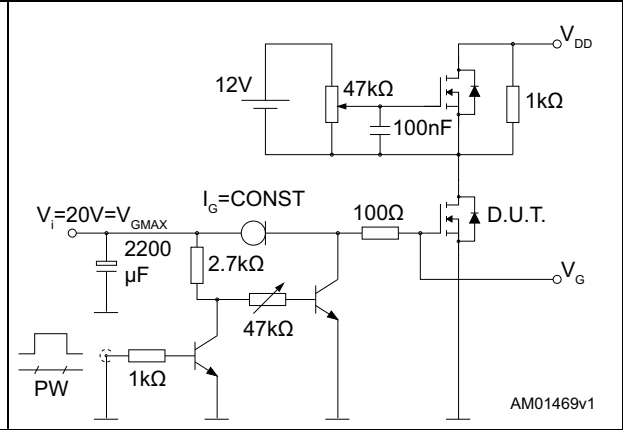
### 3 Test circuits

Figure 14. Switching times test circuit for resistive load



AM01468v1

Figure 15. Gate charge test circuit



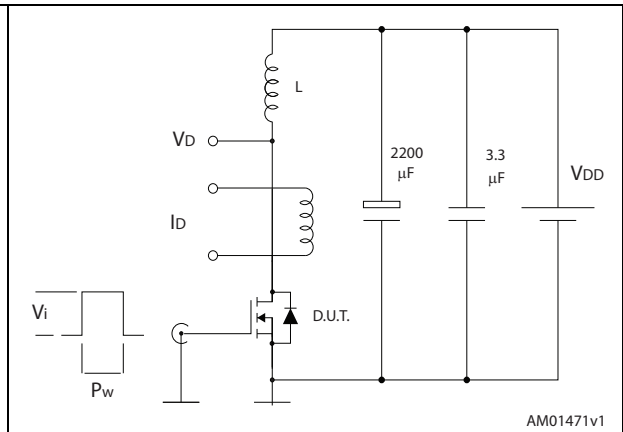
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Figure 16. Test circuit for inductive load switching and diode recovery times



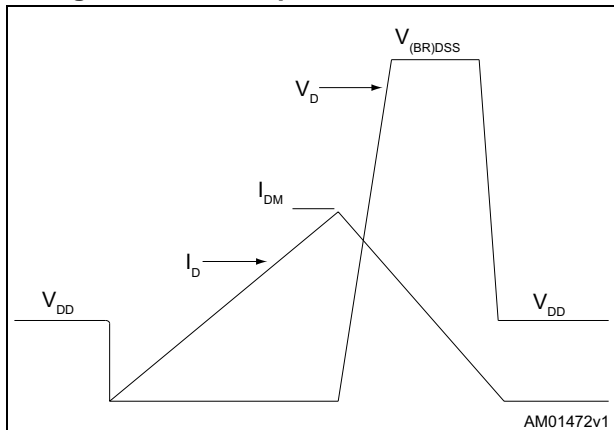
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Figure 17. Unclamped inductive load test circuit



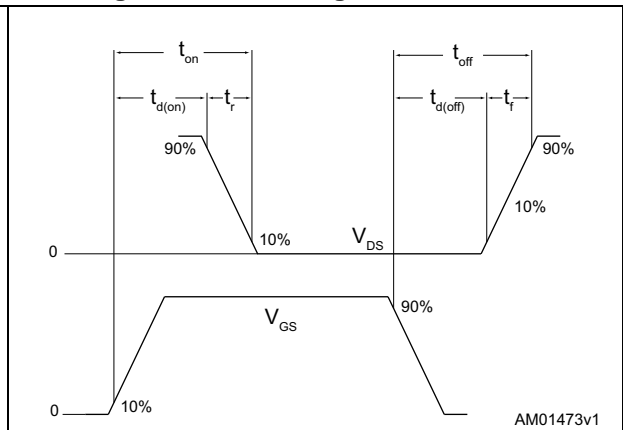
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Figure 18. Unclamped inductive waveform



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Figure 19. Switching time waveform



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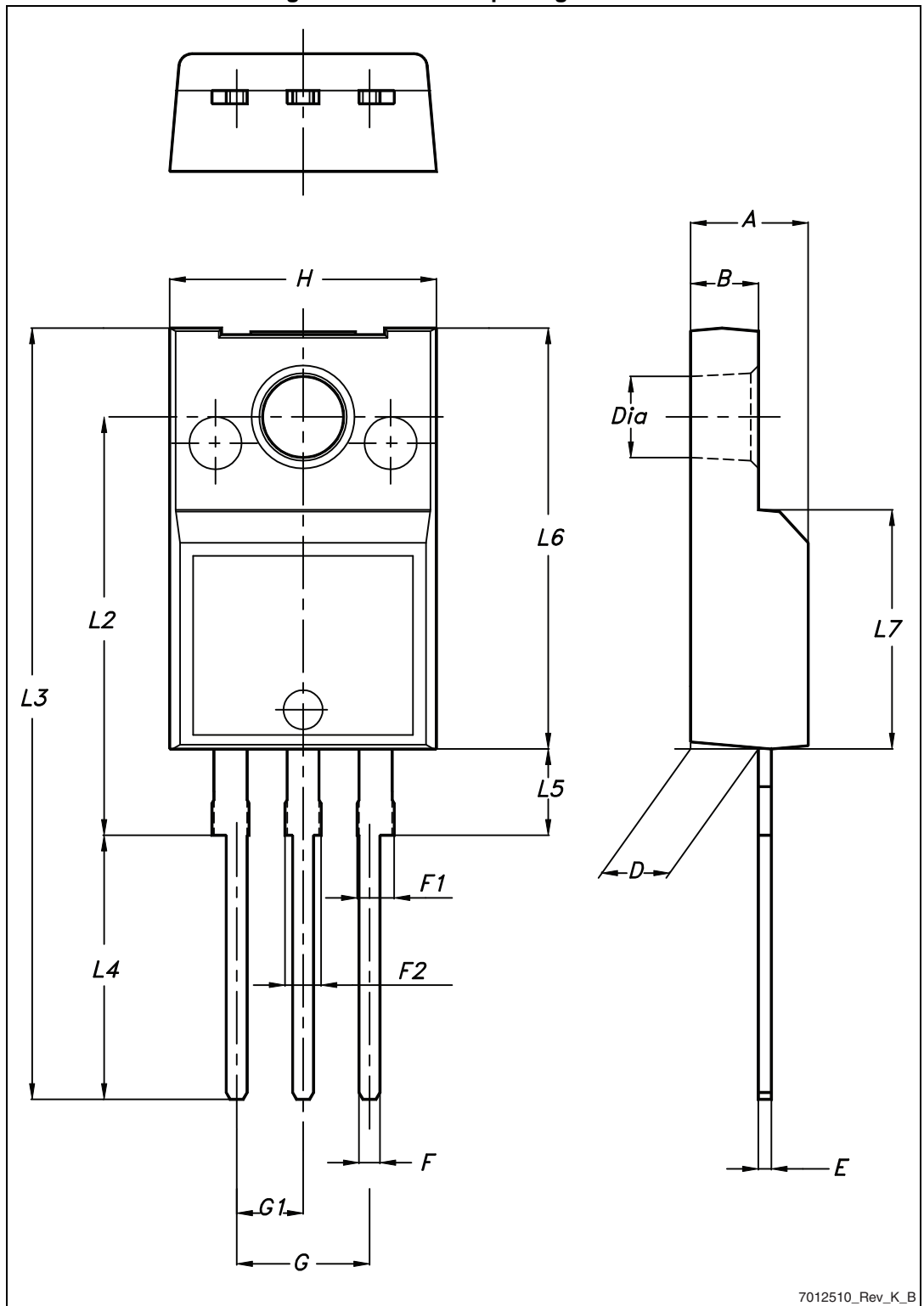


## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK<sup>®</sup> is an ST trademark.

### 4.1 TO-220FP package information

Figure 20. TO-220FP package outline



7012510\_Rev\_K\_B

Table 8. TO-220FP package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.4		4.6
B	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
H	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

## 5 Revision history

**Table 9. Document revision history**

Date	Revision	Changes
12-Sep-2014	1	First release.
03-Aug-2015	2	Text edits throughout document. Datasheet status promoted from preliminary to production data. Updated <a href="#">Table 5</a> , <a href="#">Table 6</a> and <a href="#">Table 7</a> Updated <a href="#">Figure 8</a> Updated <a href="#">Section 3: Test circuits</a>

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